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PATENT APPLICATION

1756
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of
Bernard Fay et al.

Serial No.: 09/881,026

Group Art Unit: 1756

Filed: June 15, 2002

Examiner: C. Young

For: AUTOMATED OVERLAY METROLOGY SYSTEM

Commissioner of Patents and Trademarks
United States Patent and Trademark Office
P. O. Box 1450
Alexandria, Virginia 22313-1450

AMENDMENT UNDER 37 C. F. R. §1.111

Sir:

In response to the Office Action mailed February 11, 2003, please amend the above-identified application as follows:

In the Specification:

Please substitute the following paragraphs for the corresponding paragraphs beginning at the indicated location in the specification as originally filed. A marked up copy of these paragraphs showing currently requested changes is attached as an Appendix to this response.

Page 9, line 3+:

Referring now to the drawings, and more particularly to Figures 1A, 1B and 1C, there is shown a typical box-in-box metrology feature exemplary of features for such purposes known and used in the art. The box-in-box feature 16 shown in Figure 1C is a composite feature formed by two overlaid lithographic exposures corresponding respectively to features 12 and